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# FST Simulation

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# Outline

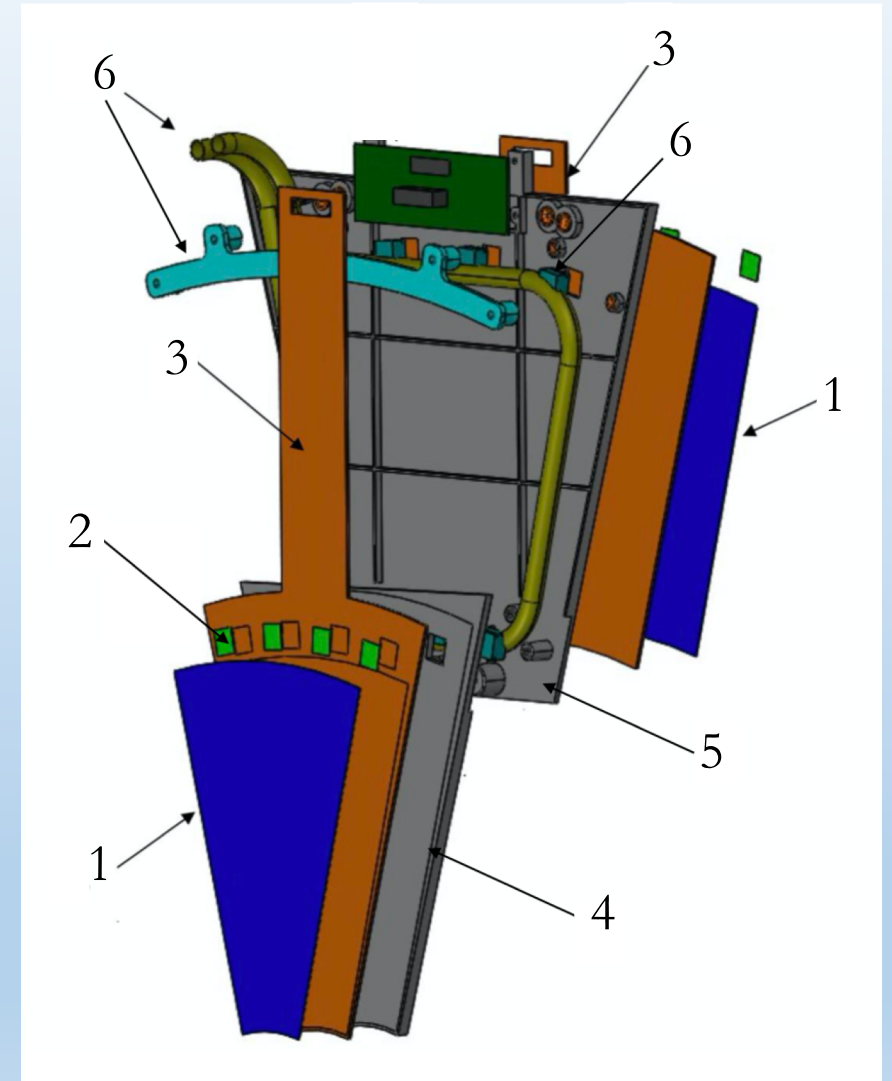
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- FST material budget
- FST simulation
  - ★ Efficiency
  - ★  $p_T$  resolution
  - ★ Secondary particle production
  - ★ Photon conversions
- Summary and outlook

# FST material budget

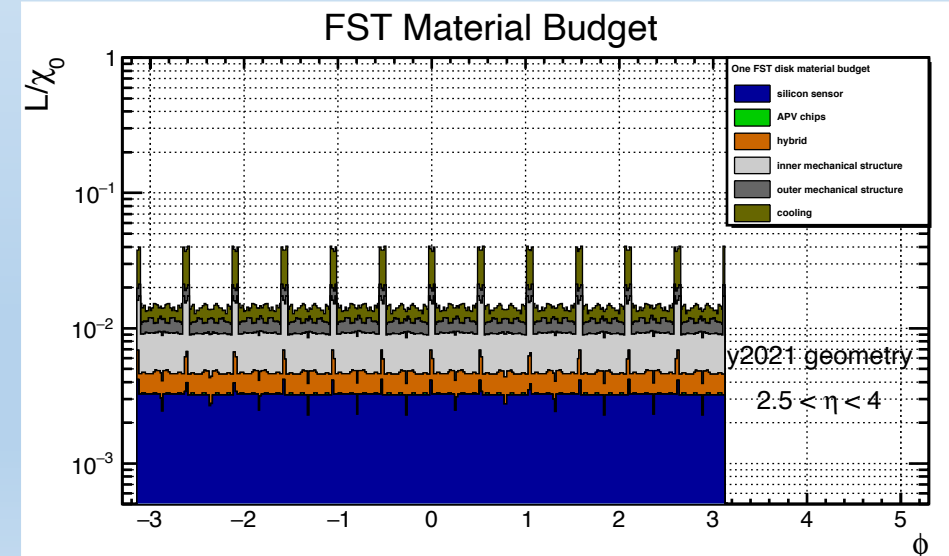
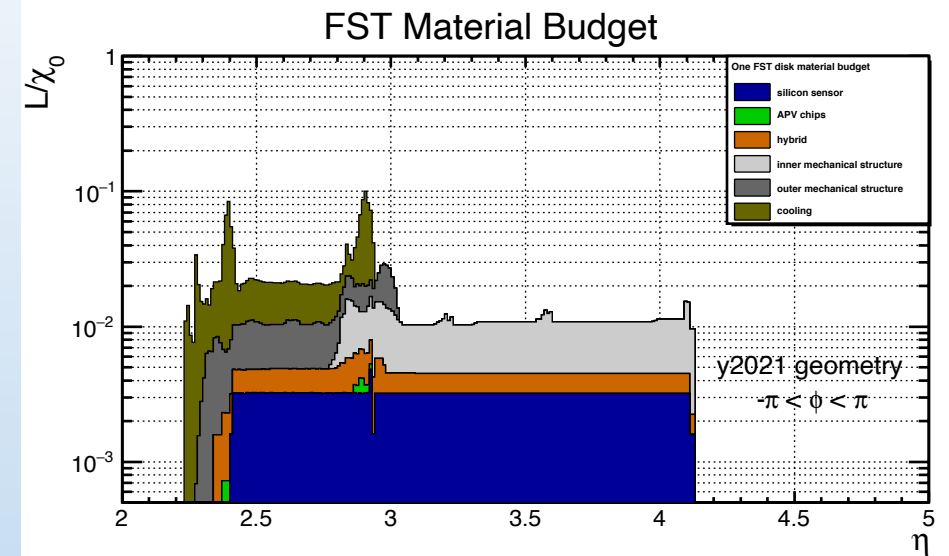
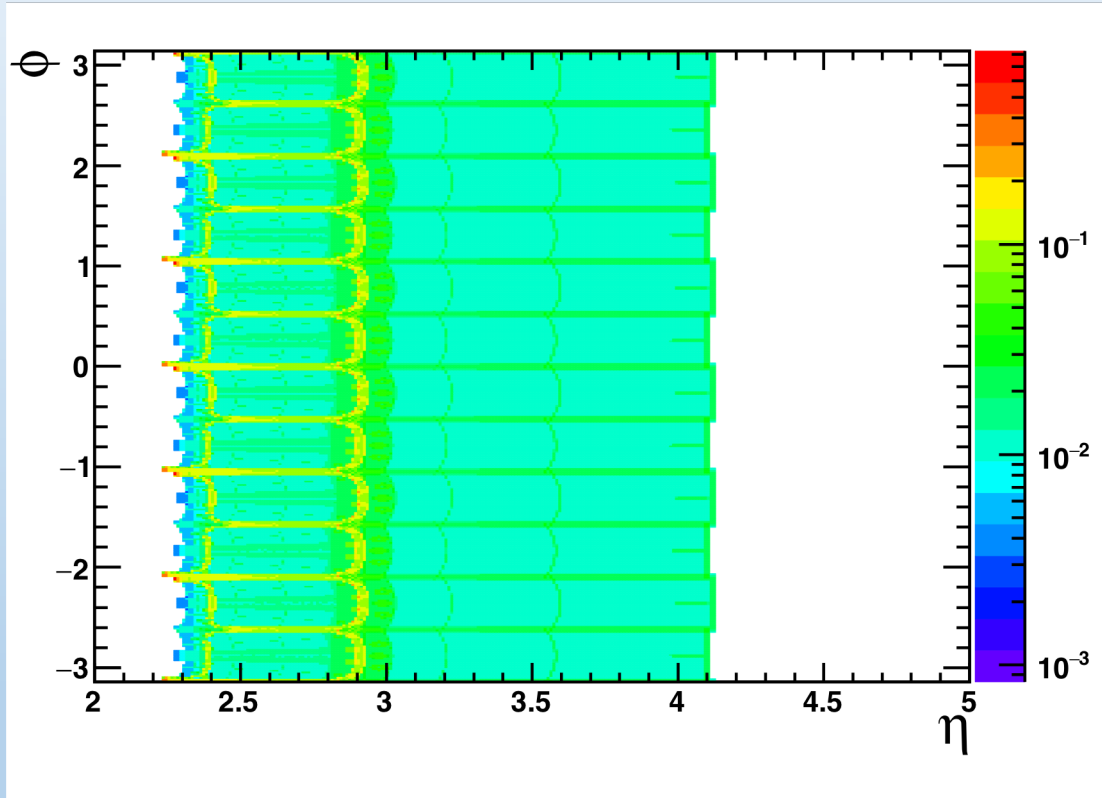
## Material classes

ID	Material
1	silicon sensor
2	APV chips
3	hybrid
4	inner mechanical structure
5	outer mechanical structure
6	cooling



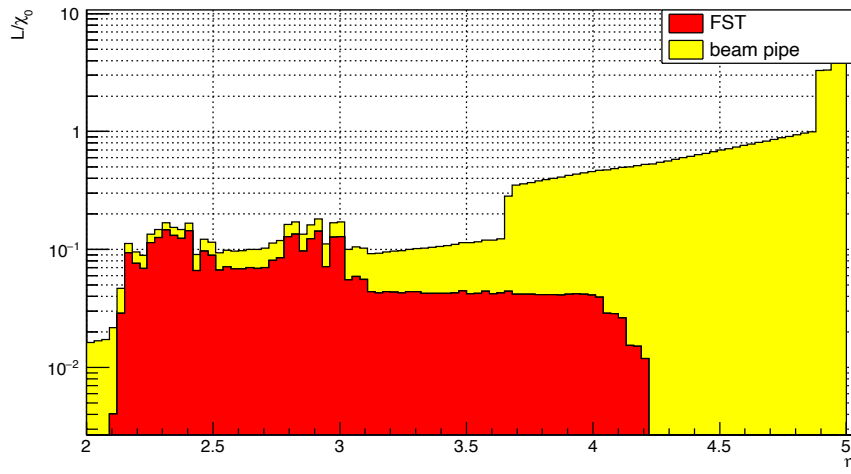
# FST material budget

❖ FST material budget for one disk ( $z = 154$  cm).

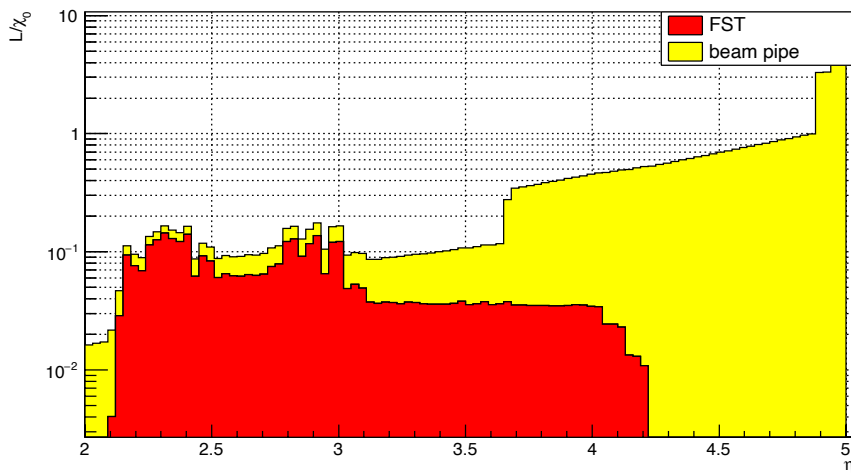


# FST material budget + beam pipe

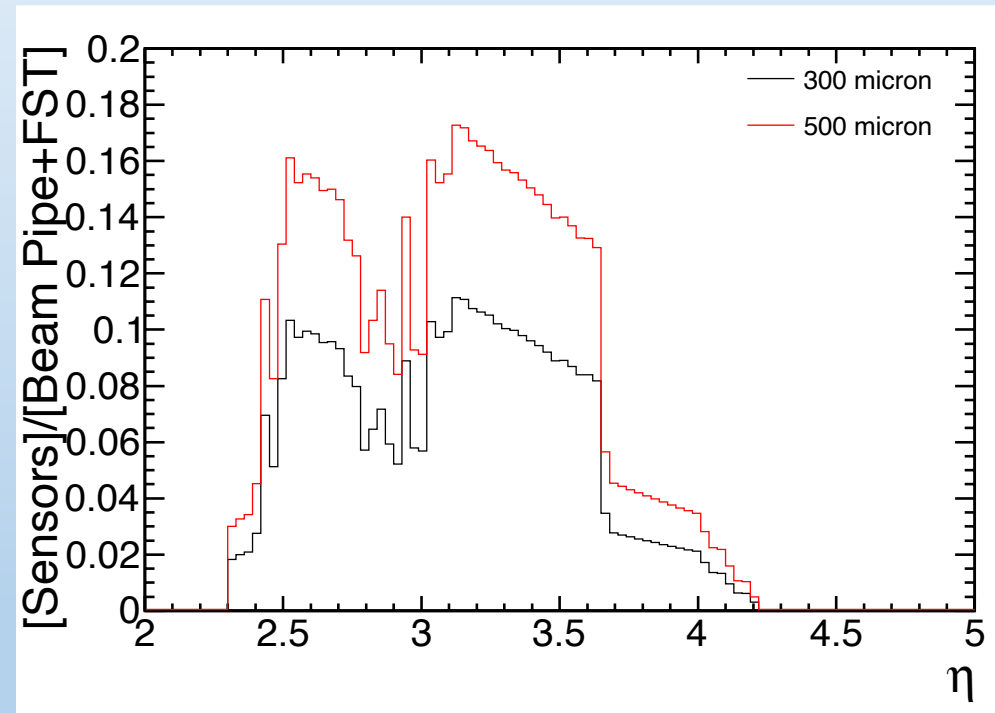
material budget histograms (500 micron)



material budget histograms (300 micron)

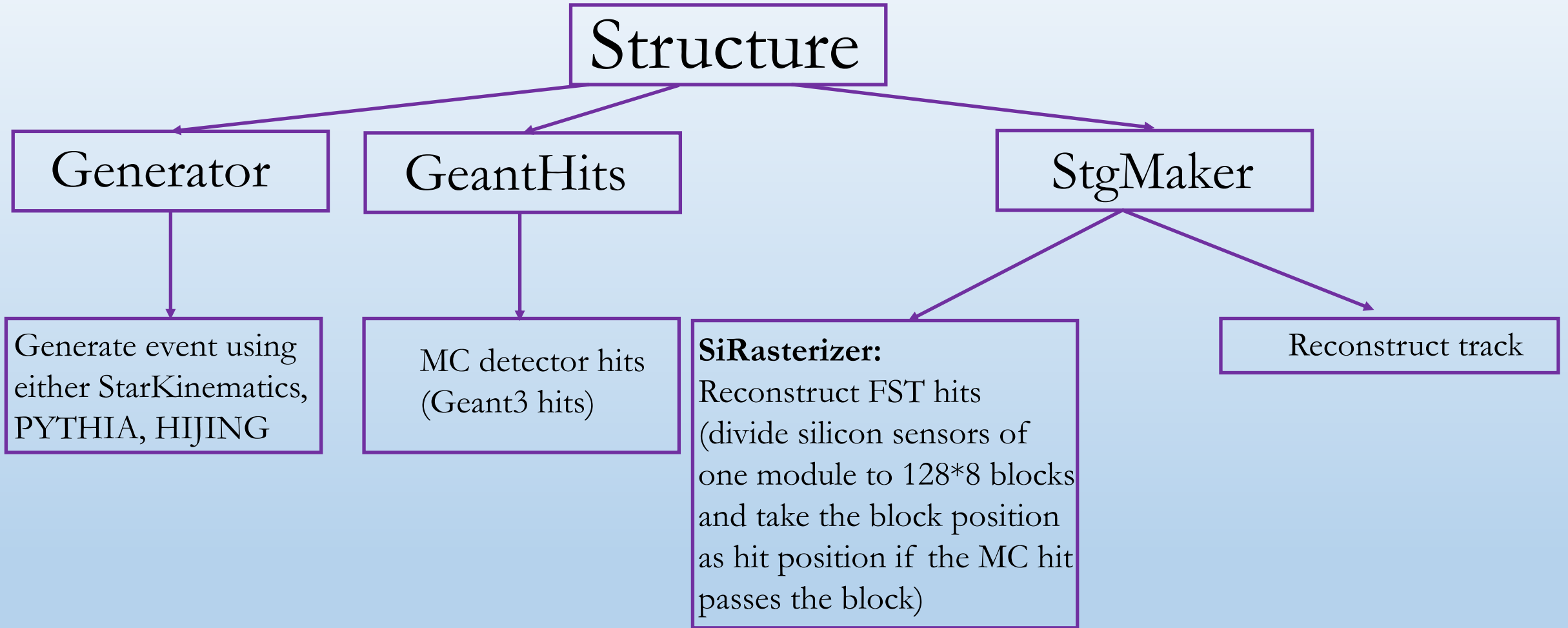


- ❖ Current thickness of silicon sensors is 300 micron.
- ❖ In order to enhance the signal (propt dX), using 500 micron thick sensors is being considered. The impact of additional materials has been checked in simulation.



~5% extra material to that of [Beam Pipe+FST] by changing from 300 to 500 micron.

# Forward Simulation and Tracking Package



# Performance

- ❖ Efficiency and  $p_T$  resolution distribution.
- ❖ Comparison for different thickness of silicon sensors.

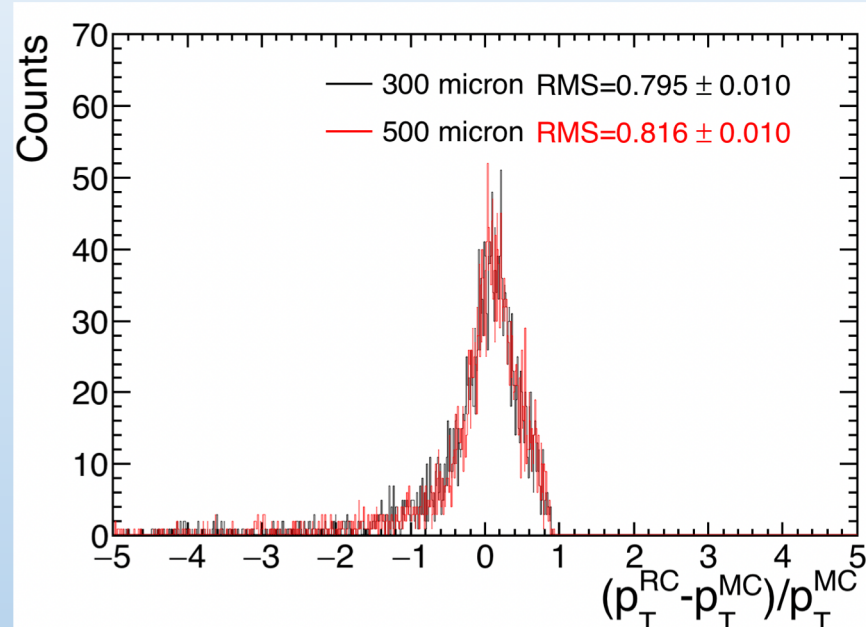
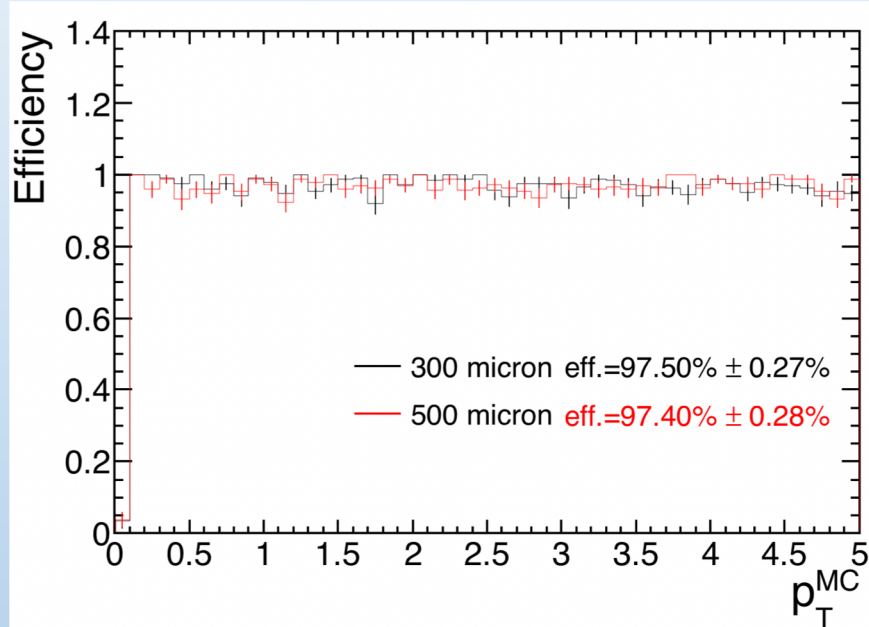
input:

1  $\mu$ -/Event

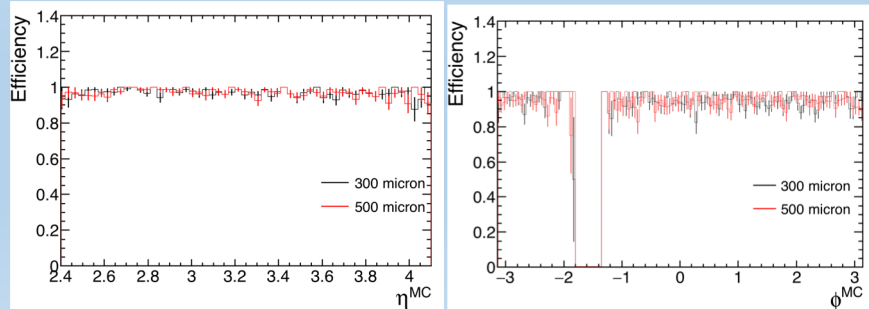
Number of events = 5000

$0.2 < p_T < 5.0$

$2.4 < \eta < 4.1$



Will plot  $(p_T^{RC} - p_T^{MC})/p_T^{MC}$  vs.  $p_T^{MC}$  after increasing the statistics.



- 1) The efficiency is 97.50% and  $p_T$  resolution is 0.795 for 300 micron.
- 2) No obvious difference between 300 and 500 micron for efficiency and  $p_T$  resolution .

# Performance

- ❖ Secondary particle production and photon conversions.
- ❖ Comparison for different thickness of silicon sensors.

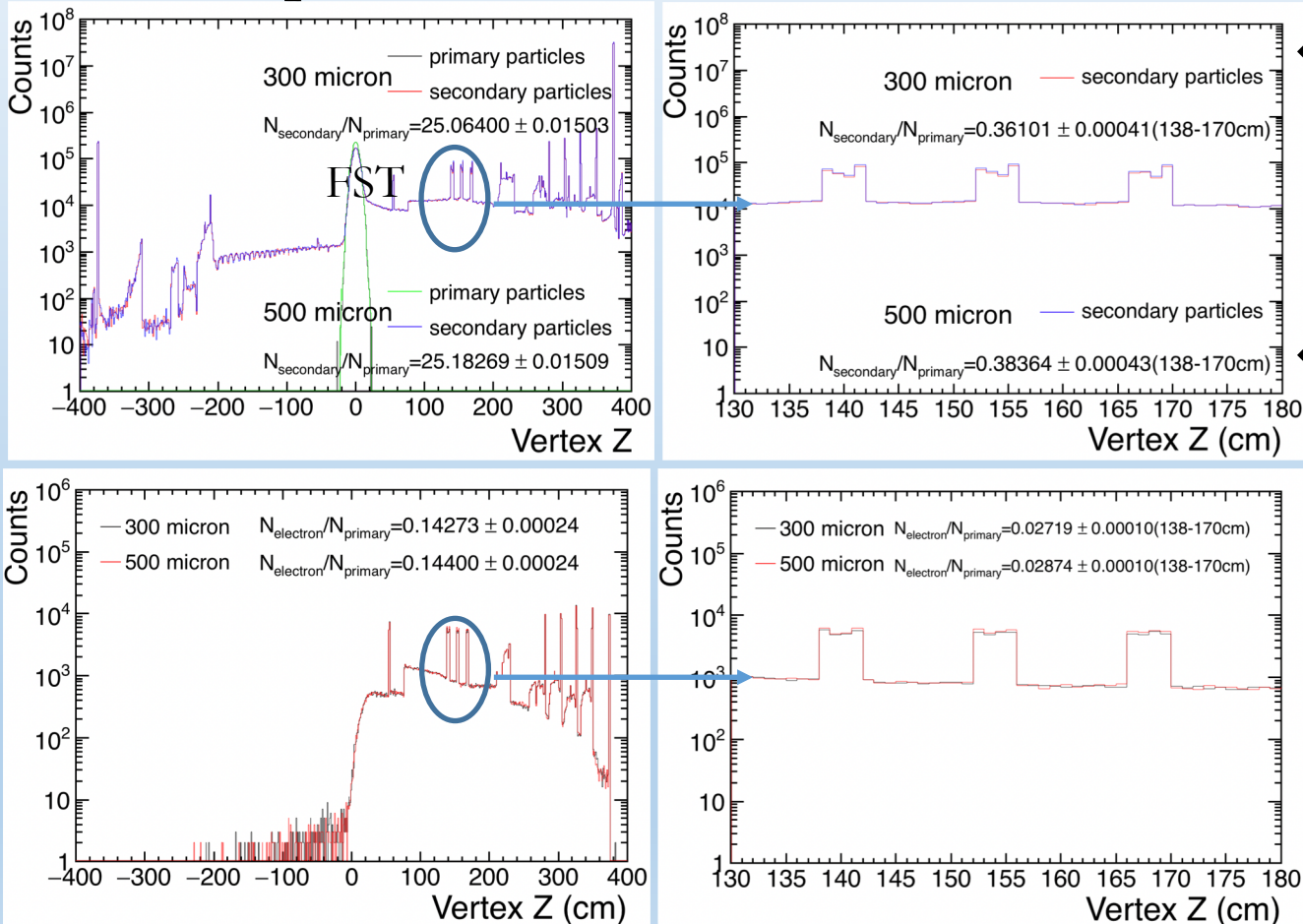
input: PYTHIA6 pp MB event

## ❖ Definition

- 1) Primary particles are produced from pp collisions directly.
- 2) Secondary particles are produced from the interaction with the materials and including those produced from decay

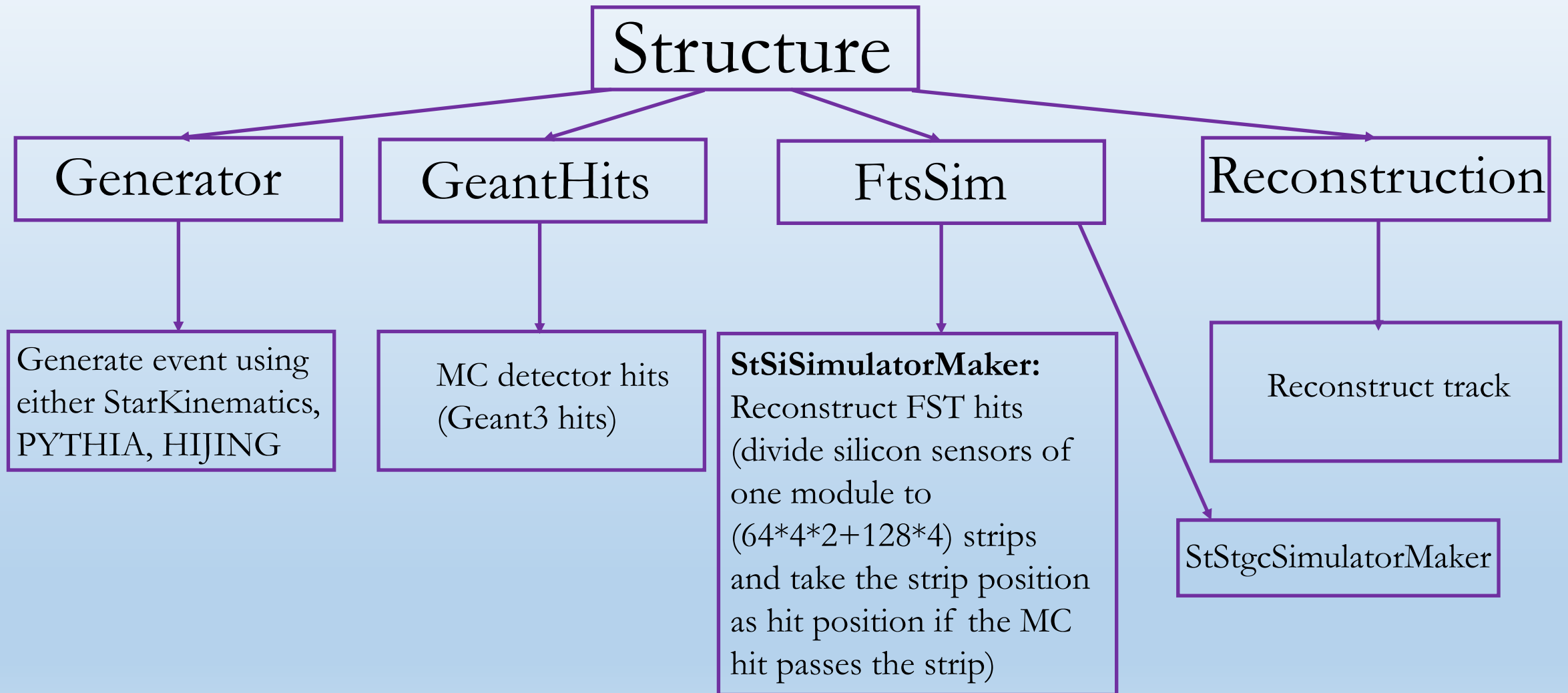
## ❖ Conclusion

- 1)  $\frac{N_{\text{secondary}}}{N_{\text{primary}}}$  of 300 micron changes by 0.5% compared with that of 500 micron.
- 2)  $\frac{N_{\text{secondary}}^{\text{FST}}}{N_{\text{primary}}}$  of 300 micron changes by 6.3% compared with that of 500 micron.
- 3)  $\frac{N_{\text{electron}}^{\text{FST}}}{N_{\text{primary}}}$  of 300 micron changes by 5.7% compared with that of 500 micron.





# Forward Simulation and Tracking Package - New



The complete package was provided by Daniel (thanks!) on 7/17/2020.

# Summary and Outlook

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## Summary

- ❖ Obtain FST material budget

~5% extra material to that of [Beam Pipe+FST] by changing from 300 to 500 micron silicon.

- ❖ Study the FST performance in STAR simulation

- 1) Efficiency,  $p_T$  resolution, secondary particle production and photon conversions.
- 2) Changes can be negligible comparing 300 micron with 500 micron thick sensors.

## Outlook

- ❖ Test the FST fast simulator with Forward tracking.

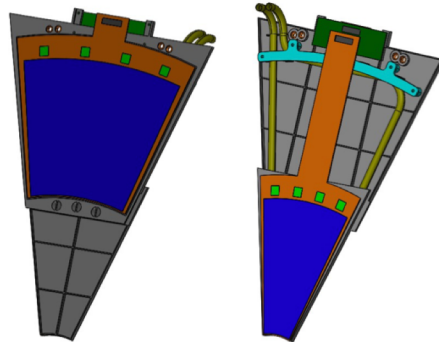
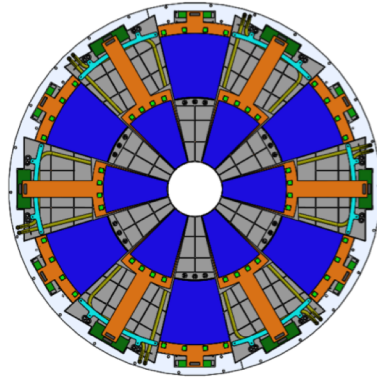
- ❖ Develop a FST slow simulator by using the efficiency and residual measured with cosmic ray (see Xu's talk).

# Back Up

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# Back Up

- Each disk: 12 modules,  $\leq 1\% X_0$
- Each module split into two regions
  - **inner region (front side)**
    - 1 Silicon microstrip sensor: each  $128 \times 4$  ( $\phi \times r$ ) strips
    - 4 APV chips
    - 1 Kapton flexible hybrid
  - **outer region (back side)**
    - 2 Silicon microstrip sensors: each  $64 \times 4$  ( $\phi \times r$ ) strips
    - 4 APV chips
    - 1 Kapton flexible hybrid
- Mechanical structure for each module
  - Made of PEEK + Carbon Fiber, with Stainless Steel cooling pipe



## Symmetric pentagon chambers

